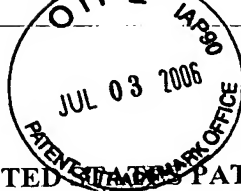


Docket No. 289130US26X PCT



MAIL STOP PCT IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Tsuyoshi MIZUNO, et al.

SERIAL NO: 10/574,547

GAU:

FILED: April 3, 2006

EXAMINER:

FOR: COATING FILM FORMING APPARATUS AND COATING FILM FORMING METHOD

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS  
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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|  |    |  |          |   |                       |  |                               |
|--|----|--|----------|---|-----------------------|--|-------------------------------|
| Form PTO 1449<br>(Modified)  |    | U.S. DEPARTMENT OF COMMERCE<br>PATENT AND TRADEMARK OFFICE   |          | ATTY DOCKET NO.<br>289130US26X PCT                      |                       | SERIAL NO.<br>10/574,547   |                               |
| LIST OF REFERENCES CITED BY APPLICANT  |    |  |          | APPLICANT<br>Tsuyoshi MIZUNO, et al.                    |                       |  |                               |
|  |    |  |          | FILING DATE<br>April 3, 2006                            |                       | GROUP  |                               |
| U.S. PATENT DOCUMENTS  |    |  |          |   |                       |  |                               |
| EXAMINER<br>INITIAL  |    | DOCUMENT<br>NUMBER   | DATE     | NAME  | CLASS                 | SUB<br>CLASS   | FILING DATE<br>IF APPROPRIATE |
|  | AA | 2004/0265493   | 12/30/04 | MIZUNO, Tsuyoshi et al.                                 |                       |  |                               |
|  | AB |  |          |   |                       |  |                               |
|  | AC |  |          |   |                       |  |                               |
|  | AD |  |          |   |                       |  |                               |
|  | AE |  |          |   |                       |  |                               |
|  | AF |  |          |   |                       |  |                               |
|  | AG |  |          |   |                       |  |                               |
|  | AH |  |          |   |                       |  |                               |
|  | AI |  |          |   |                       |  |                               |
|  | AJ |  |          |   |                       |  |                               |
|  | AK |  |          |   |                       |  |                               |
|  | AL |  |          |   |                       |  |                               |
|  | AM |  |          |   |                       |  |                               |
|  | AN |  |          |   |                       |  |                               |
| FOREIGN PATENT DOCUMENTS   |    |  |          |   |                       |  |                               |
|  |    | DOCUMENT<br>NUMBER   | DATE     | COUNTRY   | TRANSLATION<br>YES NO |  |                               |
|  | AO | 2003-168644  | 06/13/03 | JP(with English abstract)                               |                       | NO   |                               |
|  | AP | 2001-162207  | 06/19/01 | JP(with English abstract & equivalent of US 6 514 343)  |                       | NO   |                               |
|  | AQ | 2001-239199  | 09/04/01 | JP(with English abstract & equivalent of US 2002/88393) |                       | NO   |                               |
|  | AR |  |          |   |                       |  |                               |
|  | AS |  |          |   |                       |  |                               |
|  | AT |  |          |   |                       |  |                               |
|  | AU |  |          |   |                       |  |                               |
|  | AV |  |          |   |                       |  |                               |
| OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  |    |  |          |   |                       |  |                               |
|  | AW | MIZUNO, Tsuyoshi et al., "Elimination of CMP Process in BEOL by using Low-K Scan Planarization", 2003 IEEE International Symposium on Semiconductor Manufacturing (ISSM 2003) Conference Proceedings, Pages 392-395. |          |   |                       |  |                               |
|  | AX |  |          |   |                       |  |                               |
|  | AY |  |          |   |                       |  |                               |
|  | AZ |  |          |   |                       | <input type="checkbox"/> Additional References sheet(s) attached |                               |
| Examiner   |    |  |          |   | Date Considered       |  |                               |
| *Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. |    |  |          |   |                       |  |                               |

U.S. PCT Application Serial No: 10/574,547  
Filed: April 3, 2006  
Tsuyoshi MIZUNO, et al.  
Docket No. 289130 US



#### STATEMENT OF RELEVANCY

- 1) References AO -AQ have been cited in the International Search Report. A copy of these references is being submitted herewith.
- 2) References            have been cited in the corresponding            Search Report. A copy of these references is being submitted herewith.
- 3) References            are discussed in the specification. A copy of these references is being submitted herewith.
- 4) References AA & AW are additional prior art known to Applicant. A copy of these references is being submitted herewith.